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**CLEAN VERSION OF ABSTRACT**

**CIRCUIT AND METHOD FOR MEASURING AND FORCING AN INTERNAL VOLTAGE  
OF AN INTEGRATED CIRCUIT**

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Abstract of the Disclosure

C<sup>2</sup>  
A method for passing a voltage between an internal node inside a memory device and an external pin outside the memory device. The method includes passing an internal voltage from the internal node to the external pin during a read mode. The method also includes passing an external voltage from the external pin to the internal node during a force mode.

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